

Supporting information

Vacuum-depositable thiophene and benzothiadiazole based donor materials for organic solar cells

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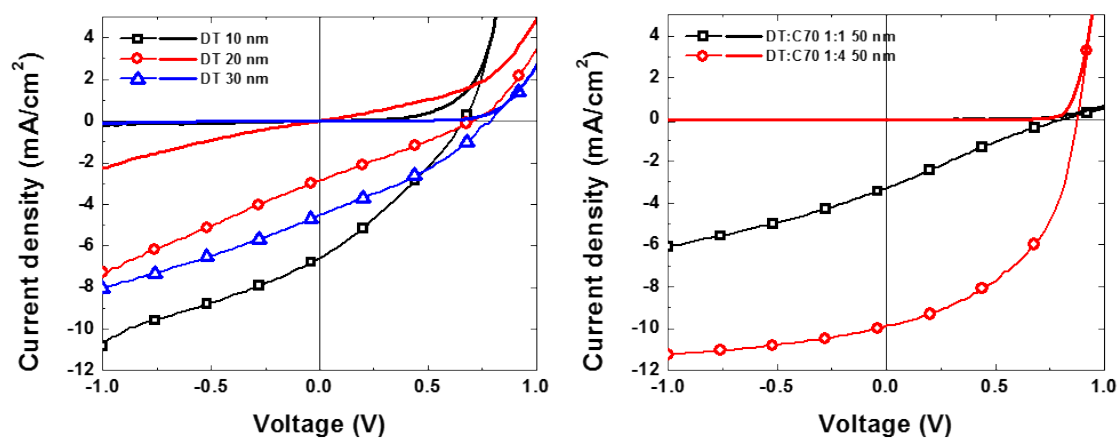


Fig. S1. J-V characteristic plots for DT based devices (left: PHJ devices, right: BHJ devices).

	<i>PCE</i> /%	J_{SC} / mA/cm ²	V_{OC} / V	<i>FF</i>	$R_p A$ / Ωcm^2	$R_s A$ / Ωcm^2
DT 10 nm	1.32	6.58	0.67	0.30	6021.19	3.00
DT 20 nm	0.54	2.85	0.71	0.27	488.21	3.77
DT 30 nm	1.17	4.53	0.79	0.33	2.96×10^4	14.16
DT:C ₇₀ 1:1 50 nm	0.60	3.29	0.81	0.23	4.49×10^4	143.30
DT:C ₇₀ 1:4 50 nm	4.13	9.89	0.86	0.48	4.44×10^7	5.29

Table S1. OPV device performances for **DT** based devices.

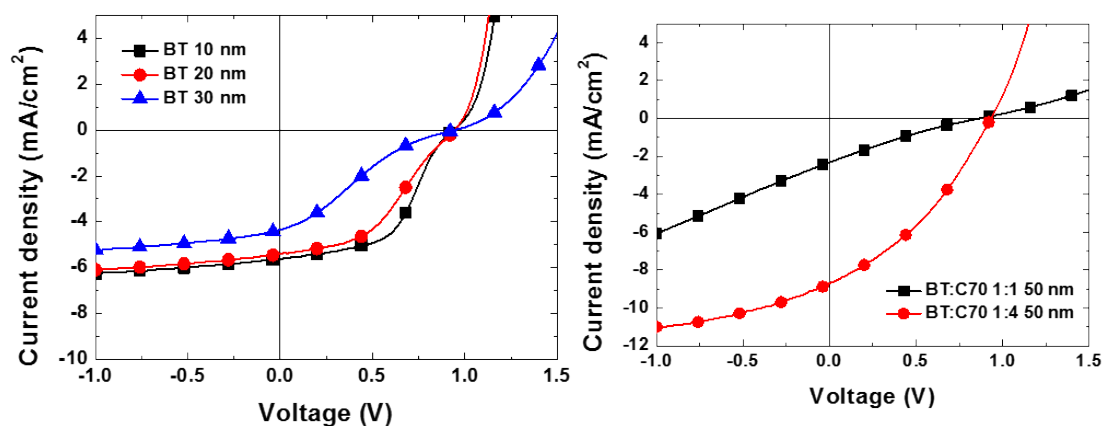


Fig. S2. J-V characteristic plots for **BT** based devices (left: PHJ devices, right: BHJ devices).

	<i>PCE</i> /%	J_{SC} / mA/cm ²	V_{OC} / V	<i>FF</i>	$R_p A$ / Ωcm^2	$R_s A$ / Ωcm^2
BT 10 nm	2.69	5.61	0.94	0.51	3.09×10^7	2.30
BT 20 nm	2.15	5.40	0.96	0.41	6.45×10^7	5.51
BT 30 nm	0.66	3.57	0.95	0.19	12.14×10^7	315.62
BT:C ₇₀ 1:1 50 nm	0.35	2.03	0.86	0.20	4.14×10^7	367.49
BT:C ₇₀ 1:4 50 nm	2.81	8.60	0.94	0.35	12.53×10^7	13.36

Table S2. OPV device performances for **BT** based devices.

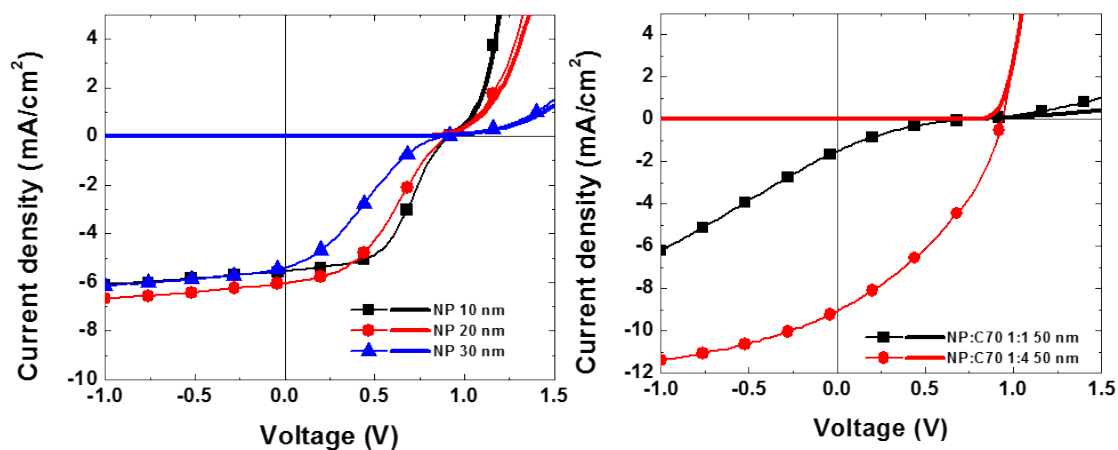


Fig. S3. J-V characteristic plots for NP based devices (left: PHJ devices, right: BHJ devices).

	<i>PCE</i> /%	J_{sc} / mA/cm ²	V_{oc} / V	<i>FF</i>	$R_p A$ / Ωcm ²	$R_s A$ / Ωcm ²
NP 10 nm	2.56	5.62	0.92	0.50	7.39×10^7	3.56
NP 20 nm	2.16	6.04	0.91	0.39	8.71×10^7	20.62
NP 30 nm	1.36	5.46	0.88	0.28	4.57×10^7	218.41
NP:C ₇₀ 1:1 50 nm	0.13	1.10	0.77	0.16	4.57×10^7	1301.53
NP:C ₇₀ 1:4 50 nm	3.11	8.99	0.93	0.37	3.24×10^7	7.92

Table S3. OPV device performance for NP based devices.

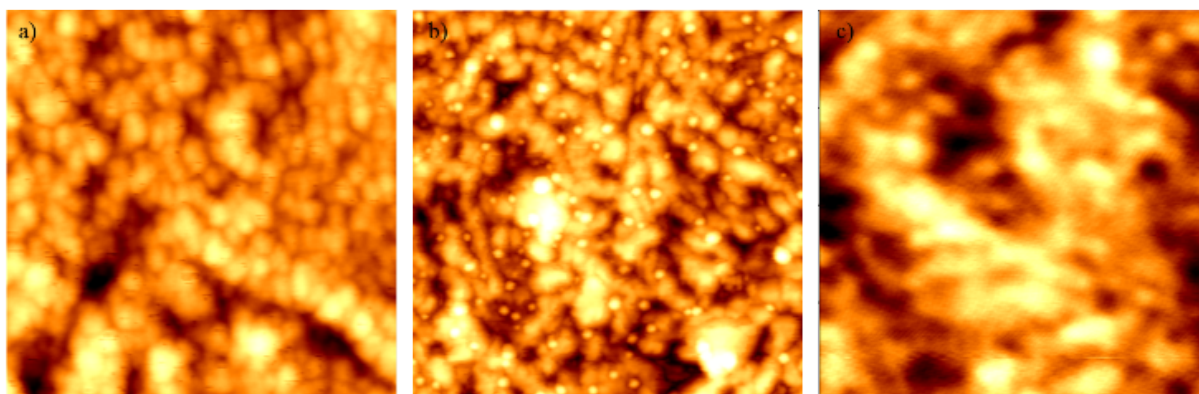


Fig. S4. AFM images of a) NP, b) BT and c) DT films. The film thickness is 10 nm and scope range is 1000 nm×1000 nm.

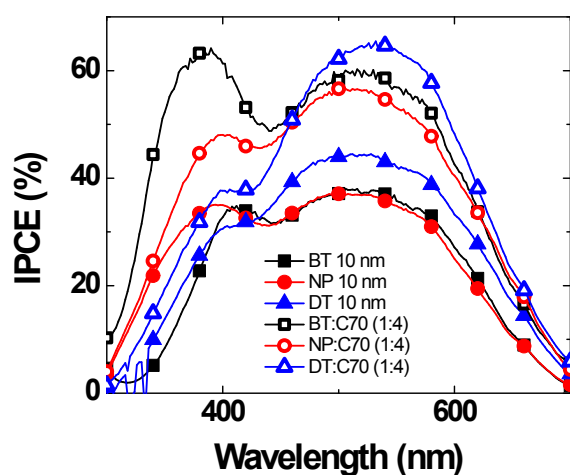


Fig. S5. IPCE data for PHJ devices (active layer thickness: 10 nm) and BHJ devices (donor:C₇₀=1:4)

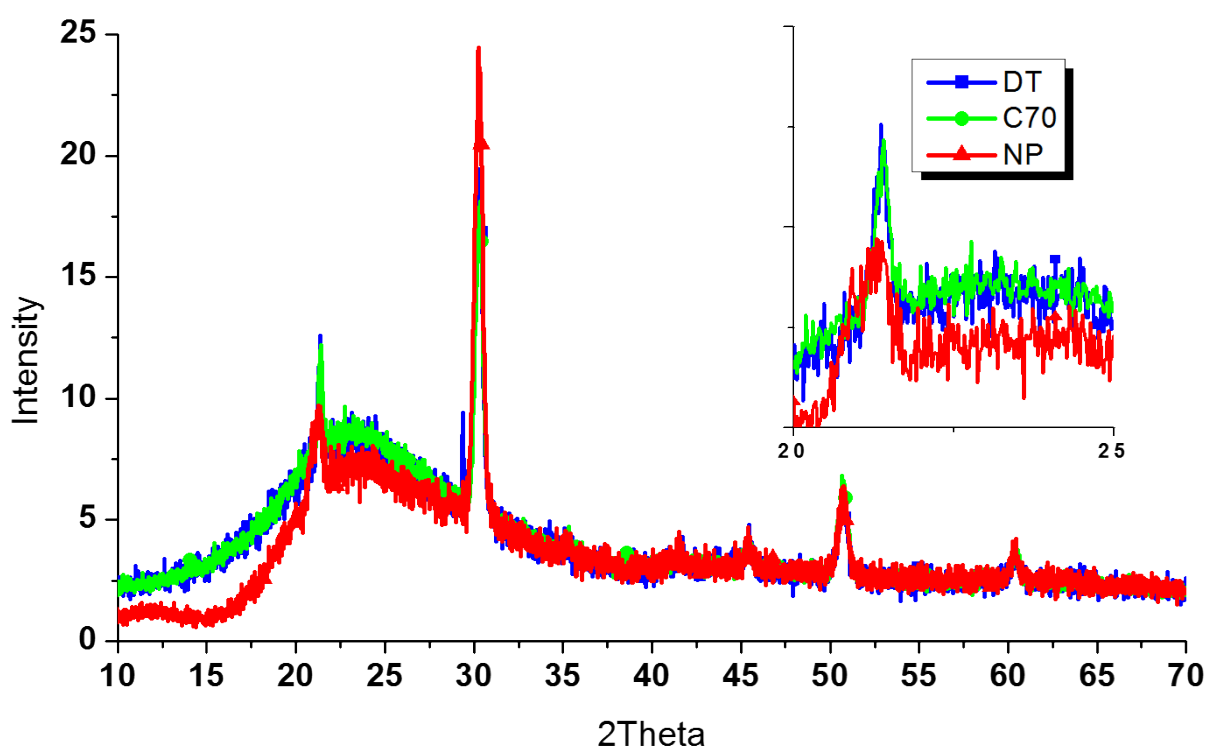


Fig. S6. X-ray diffraction spectra for C₇₀, NP:C₇₀=1:4, DT:C₇₀=1:4 blended thin film on the ITO. (Inset: enlarged spectra range from 2 θ =20 to 25). Measuring condition: detector, LYNXEYE XE (0D mode); generator: 40 kV, 40 mA; 2 θ range: 10-70 degree; step: 0.02; scan speed: 0.5 sec/step; wavelength (λ): Cu $K\alpha_1$ - 1.5418 Å.

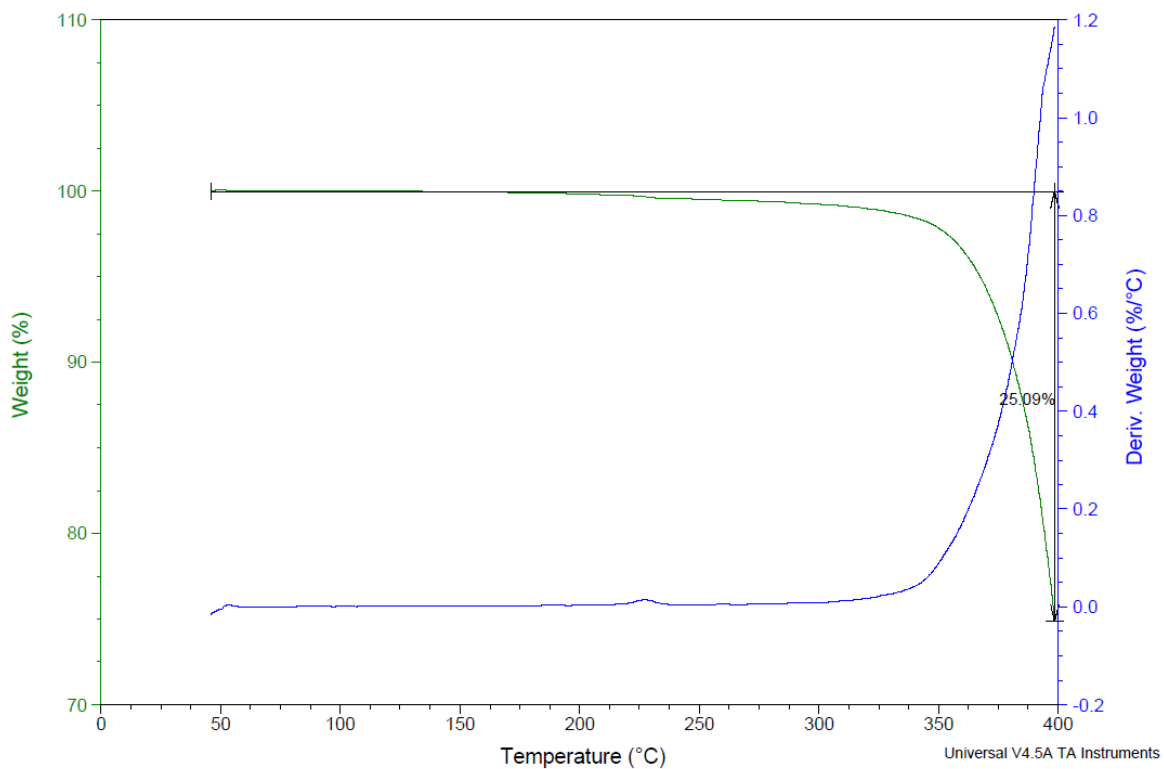


Fig. S7. TGA data for **DT**. N₂, 10 K/min.

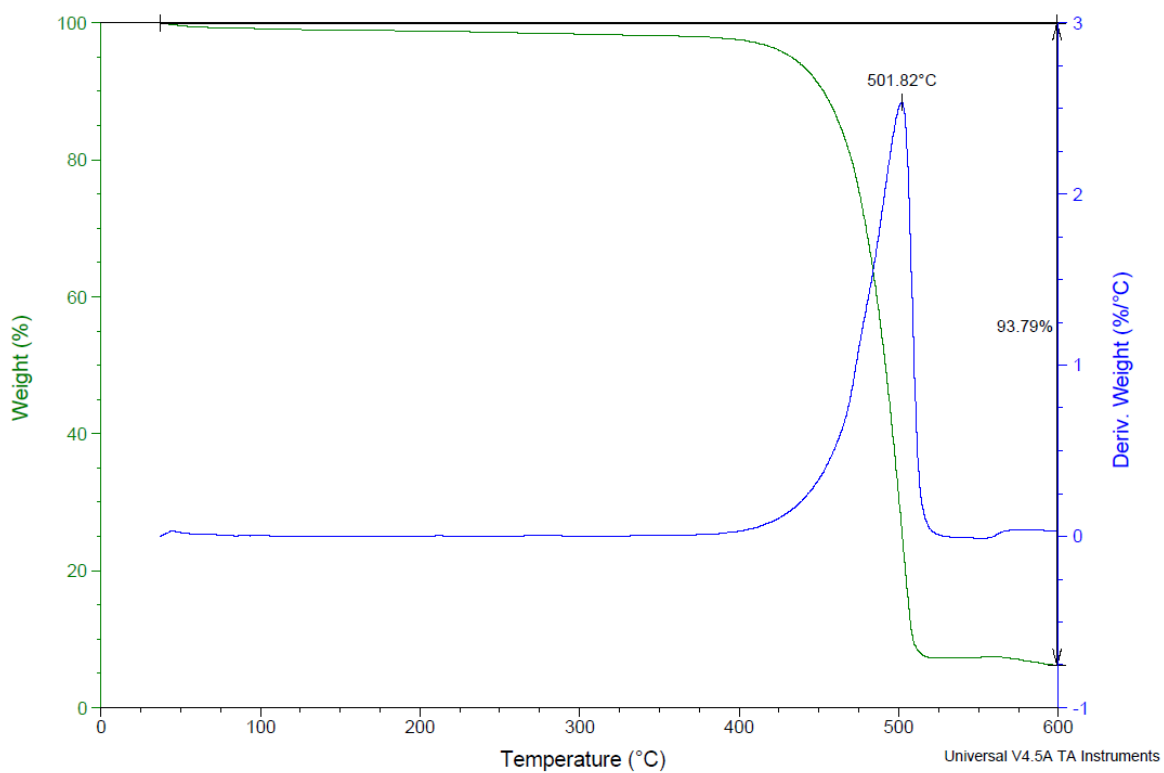


Fig. S8. TGA data for **NP**. N₂, 10 K/min.

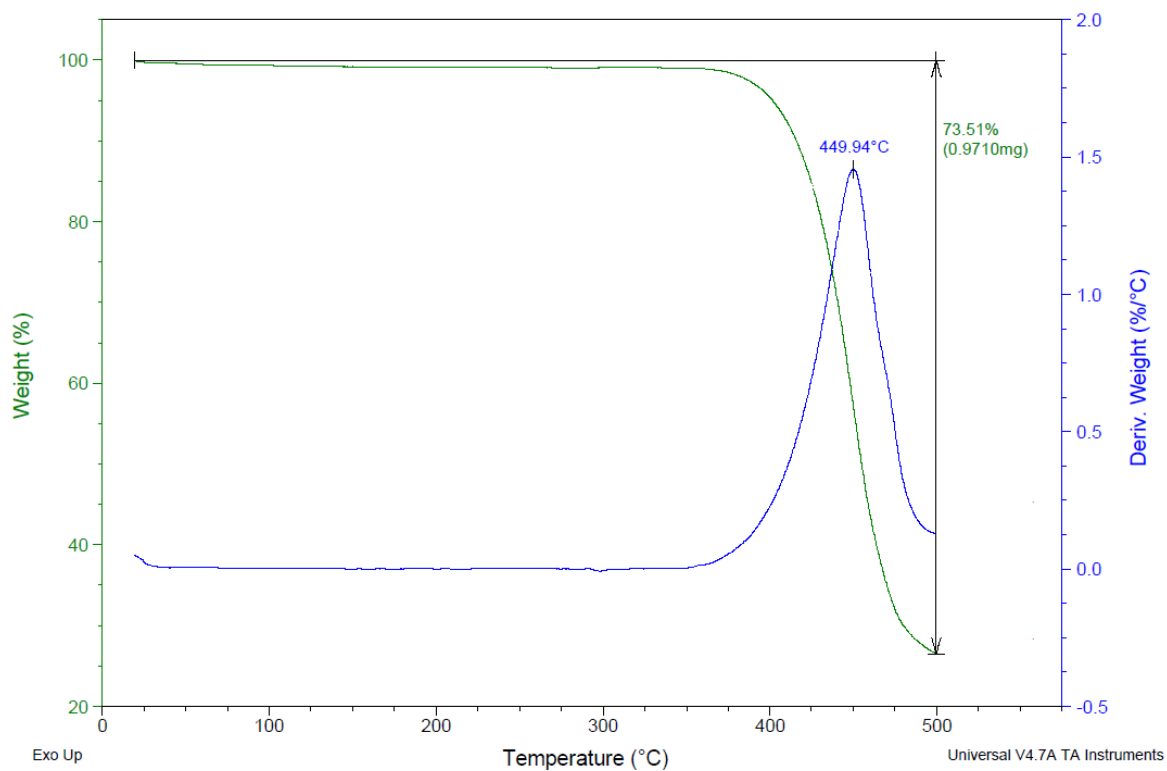


Fig. S9. TGA data for BT. N₂, 10 K/min.

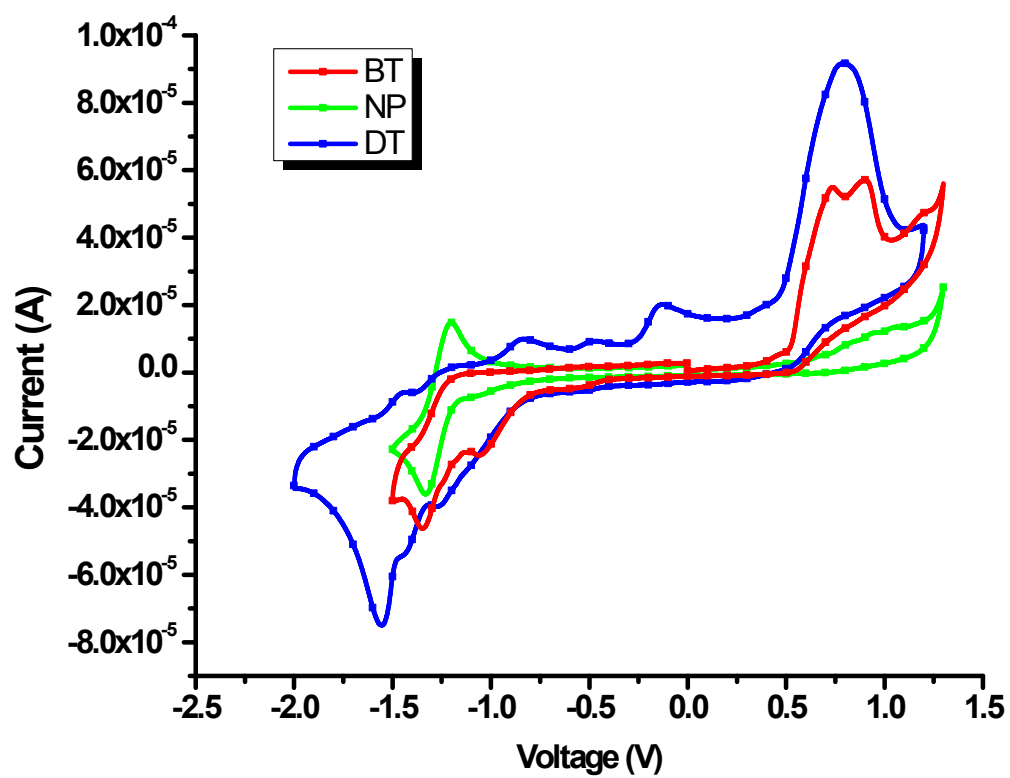


Fig. S10. CV data for BT, DT and NP.